

May 23, 2003

NEWS AND ANNOUNCEMENTS

Boeing Selects Teradyne for Next Generation (NxGen) Test Solution

With Teradyne's Spectrum™ 9000-Series functional test system as its core, the NxGen automatic test system is designed to meet exacting industry standards. Its open system architecture ensures low maintenance costs and provides an easy upgrade path for airline customers. To read more about this solution, click here:

<http://www.teradyne.com/prods/cbt/eteraview/boeing.html>

Celebrating Twenty Years of the Teradyne Users Group (TUG); Test Industry's Longest Running Customer Conference

Teradyne announced the twentieth anniversary of the founding of the Teradyne Users Group (TUG). TUG was first formed in 1983 by Teradyne customers. This year's event was held in Nashville, Tennessee, on May 5-7, where more than 250 registered attendees participated in over 100 paper sessions. The event is open to all licensed users of Teradyne's test systems and software products and is held each year at rotating locations within the U.S. For more information about this event, click here:

<http://www.teradyne.com/prods/cbt/eteraview/tug20.html>

NEMI Launches DPMO Project

The DPMO (defects per million opportunities) Project is a spin-off of NEMI's recently completed Test Strategy Project, which was chaired by Amit Verma of Teradyne. Recognizing that there was additional work on which NEMI members could collaborate beyond the scope of the initial Test Strategy Project, Verma initiated efforts to organize the DPMO project. To learn more about the DPMO project and the Test Strategy Project, click here:

http://www.teradyne.com/prods/cbt/eteraview/nemi_DMPO.html

NEMI's Test Strategy Project Releases Cost Model that Allows PCA Manufacturers to Compare Costs of Alternative Test Strategies

Teradyne has been involved with the NEMI Test Strategy Project along with five other companies who participated in the test cost model project. The test strategy cost model was designed to help printed circuit assembly manufacturers determine the financial impact of selecting a particular test strategy. To read more about the cost model and the objectives of the project, click here:

http://www.teradyne.com/prods/cbt/eteraview/nemi_costmodel.html

UPCOMING EVENTS

8th IEEE European Test Workshop, Maastricht, The Netherlands, May 25-28, 2003

The IEEE European Test Workshop (ETW) is a well-recognized forum for presenting and discussing hot topics, trends, emerging results, and practical applications in the area of electron-based circuit and system testing. Join Siegmund Hornig, Teradyne's European Sales Manager, as he co-moderates a technical session entitled, "Exploiting 1149.1 for Debug and Core Test". For full details of the technical program and for more information about the ETW, click here:

http://www.teradyne.com/prods/cbt/eteraview/euro_test.html

NEPCON East/Electro 2003 Conference, Boston, MA, June 9-11, 2003

The 2003 Conference provides breakthrough technology sessions organized by top industry associations including SMTA, IEEE, and the ESD. Alan Fraser (Teradyne's Marketing Research Manager) will participate in *EP&P* magazine's session entitled, "What's Tomorrow's Technology." Bob Stasonis (Teradyne's Industry Business Development Manager) will participate in *ASSEMBLY* magazine's session entitled, "2020 Vision: A Look into the Future of U.S. Manufacturing." For complete details regarding the technical program and event information, click here:

<http://www.teradyne.com/prods/cbt/eteraview/nepconeast.html>

PRODUCT INFORMATION

SafeTest™ Protection Technologies Web Page * New Feature *****

The SafeTest protection technologies found in Teradyne's TestStation in-circuit test system provide the only ICT solution capable of safe and reliable testing of today's new low voltage technologies. Check out our web site for a new product page focused on SafeTest Protection Technologies. Click here to find out how Teradyne can help solve the problems of testing today's exciting new low voltage devices:

<http://www.teradyne.com/prods/cbt/eteraview/safetest.html>

Introduction to SafeTest™ Protection Technology and TestStation LH™ In-Circuit Tester – Web Seminar – * Recorded Program *****

Danger - Low Voltage! Teradyne has the technology for accurate, reliable, and safe powered-up testing of new low-voltage technologies! This web seminar (presented and recorded on May 20, 2003) discusses the challenges of performing powered-up vector testing of low voltage technologies and the fundamental problems they pose to conventional in-circuit testers. It describes the ICT safe testing protection technologies, available on Teradyne's TestStation™ in-circuit testers, that are used to ensure that test vectors do not violate the increasingly tight specifications of low voltage parts. Click here to access the recorded program:

http://www.teradyne.com/prods/cbt/eteraview/safetest_webinar.html

RECENT TECHNICAL PAPERS, ARTICLES, & PUBLICATIONS

"Challenges for the Test Engineer" by Kevin L. Paton (*Printed Circuit Europe*, 1st Quarter 2003)

The manufacture of Gigabit Ethernet products is ramping up as communication systems move to an Internet Protocol-centric network, bringing new production test requirements to the manufacturing floor; whereas in the past, all Ethernet products required only electrical test, now the test engineer is faced with a standard that supports both electrical and optical capabilities. To find out what a Test Engineer can do to meet these challenges, click here:

<http://www.teradyne.com/prods/cbt/eteraview/paton.html>

"Challenges of Testing Low-Voltage Technologies at In-Circuit Test" – Technical Paper by Alan Albee presented at the Teradyne Users' Group, May, 2003

This paper discusses the challenges of performing powered-up vector testing of low voltage technologies on In-Circuit testers and the safeguards that are necessary to ensure that test vectors do not violate the increasingly tight specifications of low voltage parts. Topics include why manufacturers are adopting low voltage technologies, what happens when low voltage components are exposed to stressful conditions, design for test considerations accuracy of different ICT pin designs, and the importance of features that report and control harmful test events that can unduly stress components. To access this paper, click here:

<http://www.teradyne.com/prods/cbt/eteraview/albee.html>

"Making Strides with D2B™ (Design-to-Build) Software" – Teradyne Global Case Study

Typically working on single-digit margins, EMS companies are facing an increased number of competitors in a stagnant market where many are vying for far fewer projects than just two years ago. Using Teradyne's D2B software, Reptron Manufacturing Services of Hibbing, Minnesota, focused their attention on a process where they felt a significant improvement could be made – the conversion of CAD data into test programs. To read how Reptron was able to improve their process and the time they required to introduce new products to manufacturing, click here:

<http://www.teradyne.com/prods/cbt/eteraview/d2b.html>

“Preparing for Growth – No Strings Attached” – Teradyne Global Case Study

The much-hyped 3G broadband wireless standard is finally coming to market through a groundbreaking development project by IPWireless, Inc., San Bruno, California. Although U.S. based, the company chose to undertake a very aggressive design and development phase in Europe, supported by Test Solutions Ltd. (a European Test Specialist and Teradyne Authorized Representative). Teradyne's Spectrum™ test system and the capabilities of its TestStudio™ software were instrumental in helping IPWireless achieve its goals. To read more about this project, click here:

<http://www.teradyne.com/prods/cbt/eteraview/ipwireless.html>

“PXISA Updates – Spring 2003 – The President's Corner” by Bob Stasonis, Industry Business Development Manager, Teradyne (PXI Technology Review/Spring 2003)

As president of the PXI Systems Alliance (PXISA), Bob is involved in advancing the technology of PXI architecture and has been working with PXISA members in the creation and evolution of hardware and software specifications. Click here for Bob's update on the status of this endeavor:

http://www.teradyne.com/prods/cbt/eteraview/pxisa_update.html

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